

12-Bit, 65 MSPS Monolithic A/D Converter

AD6640

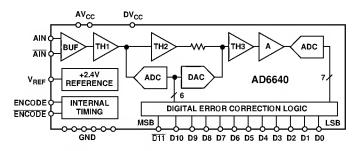
FEATURES

65 MSPS Minimum Sample Rate
80 dB Spurious-Free Dynamic Range
IF-Sampling to 70 MHz
695 mW Power Dissipation
Single +5 V Supply
On-Chip T/H and Reference
Twos Complement Output Format
3.3 V or 5 V CMOS-Compatible Output Levels

APPLICATIONS

Cellular/PCS Base Stations Multichannel, Multimode Receivers GPS Anti-J amming Receivers Communications Receivers

FUNCTIONAL BLOCK DIAGRAM



PRODUCT DESCRIPTION

The AD 6640 is a high speed, high performance, low power, monolithic 12-bit analog-to-digital converter. All necessary functions, including track-and-hold (T/H) and reference are included on-chip to provide a complete conversion solution. The AD 6640 runs on a single +5 V supply and provides C M O S-compatible digital outputs at 65 M SPS.

Specifically designed to address the needs of multichannel, multimode receivers, the AD 6640 maintains 80 dB spurious-free dynamic range (SFDR) over a bandwidth of 25 MHz. Noise performance is also exceptional; typical signal-to-noise ratio is 68 dB.

The AD 6640 is built on Analog D evices' high speed complementary bipolar process (XFCB) and uses an innovative multipass architecture. Units are packaged in a 44-terminal Thin Quad Plastic Flatback (TQFP) specified from -40°C to $+85^{\circ}\text{C}$.

PRODUCT HIGHLIGHTS

- 1. Guaranteed sample rate is 65 M SPS.
- 2. Fully differential analog input stage specified for frequencies up to 70 M H z; enables "IF-Sampling."
- 3. Low power dissipation: 695 mW off a single +5 V supply.
- 4. Digital outputs may be run on +3.3 V supply for easy interface to digital ASICs.
- 5. Complete Solution: reference and track-and-hold.
- 6. Packaged in small, surface mount, plastic 44-terminal TQFP.

AD6640-SPECIFICATIONS

DC SPECIFICATIONS (AVCC = +5 V, DVCC = +3.3 V; $T_{MIN} = -40^{\circ}C$, $T_{MAX} = +85^{\circ}C$)

Parameter	Temp	Test Level	Min	AD 6640AST Typ	Max	Units
RESOLUTION	Temp	Ecva	1-1111	12	Mux	Bits
ACCURACY No Missing Codes Offset Error Gain Error Differential Nonlinearity (DNL) Integral Nonlinearity (INL)	Full Full Full Full Full	VI VI VI V	-10 -10 -1.0	±3.5 4.0 ±0.3 ±1.5	+10 +10 +1.5	mV % FS LSB LSB
TEM PERATURE DRIFT Offset Error Gain Error	F ull F ull	V		10 100		ppm/°C ppm/°C
POWER SUPPLY REJECTION (PSRR)	Full	V		±0.5		mV/V
REFERENCE OUT (VREF) ¹	+25°C	V		2.4		V
ANALOG INPUTS (AIN, AIN) Differential Input Voltage Range Differential Input Resistance Differential Input Capacitance	Full Full +25°C	IV V	0.7	2.0 0.9 1.5	1.1	V p-p kΩ pF
POWER SUPPLY Supply Voltage AVCC DVCC Supply Current I _{AVCC} (AVCC = 5.0 V) I _{DVCC} (DVCC = 3.3 V) Total I _{CC}	Full Full Full Full Full	VI VI V V	4.75 3.0	5.0 3.3 139	5.25 5.25 175	V V mA mA mW
POWER CONSUMPTION	, Full	νĺ	DCF.	695	875	mW

NOTES ¹TO COME.

Specifications subject to change without notice.

DIGITAL SPECIFICATIONS (AVCC = +5 V, DVCC = +3.3 V; T_{MIN} = -40°C, T_{MAX} = +85°C)

Parameter	Temp	Test Level	Min	AD 6640AST Typ	Max	Units
LOGIC INPUTS (ENC, ENC) ¹						
Differential Input Voltage	Full	IV	0.4	1.0	5.0	l v
Logic Compatibility ²	Full	IV		TTL/CM OS		
Logic "1" Voltage	Full	VI	2.0	·	5.0	l v
Logic "0" Voltage	Full	VI	0		0.8	V
Logic "1" Current $(V_{INH} = 5 V)$	Full	VI	450	625	800	μΑ
Logic "0" Current $(V_{INL} = 0 V)$	Full	VI	-400	-300	-200	μA
Input C apacitance	+25°C	V		2.5		pF
LOGIC OUTPUTS (D11-D0)						
Logic Compatibility				CMOS		
Logic "1" Voltage (DVCC = $+3.3 \text{ V}$)	Full	VI	2.5	2.9		V
Logic "0" Voltage (DVCC = $+3.3 \text{ V}$)	Full	VI		0.25	0.8	V
Logic "1" Voltage (DVCC = $+5.0 \text{ V}$)	Full	IV	4.0	4.6		V
Logic "0" Voltage (DVCC = $+5.0 \text{ V}$)	Full	IV		0.4	0.8	V
Output Coding			T wos C omplement			

NOTES

¹TO COME.

²TO COME.

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SWITCHING SPECIFICATIONS (AVCC = +5 V, DVCC = +3.3 V; ENCODE & $\overline{\text{ENCODE}}$ = 65 MSPS; T_{MIN} = -408C, TMAX = +85°C)

Parameter (Conditions)	Temp	Test Level	Min	AD 6640AST Typ	Max	Units
M aximum Conversion Rate	Full	VI	65			M SPS
M inimum Conversion Rate	Full	IV			5	M SPS
Aperture D elay (t _A)	+25°C	V		-250		ps
Aperture Uncertainty (Jitter)	+25°C	V		0.3		ps rms
ENCODE Pulse Width High ¹	+25°C	IV	7			ns .
ENCODE Pulse Width Low	+25°C	IV	7			ns
Output D elay (top) DVCC +3.3 V ²	Full	IV	4.2	6.0	8.6	ns
Output Delay (t _{OD}) DVCC +5.0 V	Full	IV	4.0	8.0	14.0	ns

NOTES

AC SPECIFICATIONS¹ (AVCC = +5 V, DVCC = +3.3 V; ENCODE & ENCODE = 65 MSPS; T_{MIN} = -408C, T_{MAX} = +85°C)

	Test			AD 6640AST		
Parameter (Conditions)	Temp	Level	Min	Тур	Max	Units
SN R Analog Input 2.2 M H z @ -1 dBFS 15.5 M H z 31.0 M H z 69.0 M H z	+25°C +25°C +25°C +25°C	V I V V	64	68 67 67 66		dB dB dB dB
SIN A D A nalog Input 2.2 M H z @ -1 dBFS 15.5 M H z 31.0 M H z 69.0 M H z	+25°C +25°C +25°C +25°C	V I V	63.5	67.5 66.5 66.5 65		dB dB dB dB
W orst H armonic (2nd or 3rd) Analog Input 2.2 M H z @ -1 dBFS 15.5 M H z 31.0 M H z 69.0 M H z	+25°C +25°C +25°C +25°C	V I V	74	80 80 79 77		dBc dBc dBc dBc
W orst H armonic (4th or H igher) A nalog I nput 2.2 M H z @ -1 dBFS 15.5 M H z 31.0 M H z 69.0 M H z	+25°C +25°C +25°C +25°C	V V V		86 86 85 84		dBc dBc dBc dBc
M ultitone SFDR (w/Dither) ² Eight Tones @ -20 dBFS	Full	V		90		dBFS
T wo-T one IM D Rejection F1, F2 @ -7 dBFS	Full	V		80		dBc
Analog Input Bandwidth	+25°C	V		240		MHz
T ransient Response	+25°C	V		10		ns
O vervoltage R ecovery T ime	+25°C	V		20		ns

NOTES

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 $^{^1}$ All ac specifications tested by driving ENCODE and $\overline{
m ENCODE}$ differentially.

²Analog Input signal power swept from -20 dBFS to -95 dBFS; Dither power = -32.5 dBm.

Specifications subject to change without notice.

 $^{^1\!}$ All ac specifications tested by driving ENCODE and $\overline{\mathrm{ENCODE}}$ differentially.

 $^{^{2}}$ Analog Input signal power swept from -20 dBFS to -95 dBFS; Dither power = -32.5 dBm.

Specifications subject to change without notice.

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WAFER TEST LIMITS¹ (AV_{cc} = DV_{cc} = +5 V; ENCODE = 20 MSPS unless otherwise noted)

Parameter	Temp	AD 6640CHIPS Min	S Max	Units
POWER SUPPLY I _{CC} Supply Current	+25°C	100	175	mA
ENCODE Input Logic "1" Current Logic "0" Current	+25°C +25°C	450 -400	800 -200	μ Α μ Α
DC ACCURACY Offset Error Gain Error No Missing Codes Differential Nonlinearity	+25°C +25°C +25°C +25°C	-10 -10 G uaranteed -0.995	10 10	mV % FS LSB

NOTES

ABSOLUTE MAXIMUM RATINGS¹

Parameter	Min	Max	Units
ELECTRICAL			
AV _{CC} Voltage	0	7	V
DV _{CC} Voltage	0	7	٧
Analog Input Voltage	0.5	4.5	٧
Analog Input Current		20	mA
Digital Input Voltage (ENCODE)	0	AV_{CC}	٧
ENCODE, ENCODE Differential			
Voltage		4	V
Digital Öutput Current	-40	40	mA
ENVIRONMENTAL ²	\sim		
O perating T emperature R ange	- 3		
(Ambient)	-40	+85	°C
M aximum Junction T emperature		+150	°C
L ead T emperature (Soldering, 10 sec)		+300	°C
Storage Temperature Range (Ambient)	-65	+150	°C

NOTES

EXPLANATION OF TEST LEVELS Test Level

- I 100% production tested.
- 100% production tested at +25°C, and sample tested at specified temperatures. AC testing done on sample basis.
- III Sample tested only.
- Parameter is guaranteed by design and characterization testing.
- Parameter is a typical value only.
- VI All devices are 100% production tested at +25°C; sample tested at temperature extremes.

ORDERING GUIDE

Model	Temperature Range Package Description		Package Option	
AD 6640AST AD 6640CHIPS AD 6640ST/PCB	-40°C to +85°C (Ambient) -40°C to +85°C (Ambient)	44-T erminal TQFP (Thin Quad Plastic Flatpack) Unpackaged Die Evaluation Board with AD6640AST	ST -44	

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CAUTION.

ESD (electrostatic discharge) sensitive device. Electrostatic charges as high as 4000 V readily accumulate on the human body and test equipment and can discharge without detection. Although the AD 6640 features proprietary ESD protection circuitry, permanent damage may occur on devices subjected to high energy electrostatic discharges. Therefore, proper ESD precautions are recommended to avoid performance degradation or loss of functionality.



¹Electrical test is performed at wafer probe to the limits shown. Due to variations in assembly methods and normal yield loss, yield after packaging is not guaranteed for standard product dice.

²Die substrate is connected to 0 V.

¹Absolute maximum ratings are limiting values to be applied individually, and beyond which the serviceability of the circuit may be impaired. Functional operability is not necessarily implied. Exposure to absolute maximum rating conditions for an extended period of time may affect device reliability.

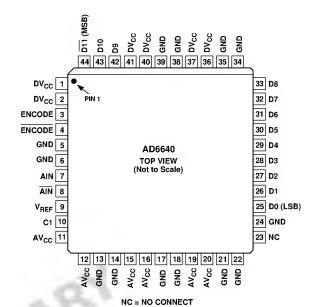
²T ypical thermal impedances (44-terminal TQFP); $\theta_{JA} = 55$ °C/W.

PIN FUNCTION DESCRIPTIONS

Pin No.	Name	Function
1, 2	DV _{CC}	+3.3 V/+5 V Power Supply (Digital). Powers output stage only.
3	ENCODE	Encode input. Data conversion initiated on rising edge.
4	ENCODE	Complement of ENCODE. Drive differentially with ENCODE or bypass to Ground for single-ended clock mode.
5, 6	GND	G round.
7	AIN	Analog Input.
8	$\overline{ ext{AIN}}$	Complement Analog Input.
9	V_{REF}	Internal Voltage Reference. Nominally +2.4 V. Bypass to Ground with 0.1 μF + 0.01 μF microwave chip cap.
10	C1	Internal Bias Point. Bypass to ground with 0.01 μF cap.
11, 12	AV_CC	+5 V Power Supply (Analog).
13, 14	GND	G round.
15, 16	AV_{CC}	+5 V Power Supply (Analog).
17, 18	GND	Ground.
19, 20	AV_{CC}	+5 V Power Supply (Analog).
21, 22	GND	Ground.
23	NC	N o C onnect.
24	GND	Ground.
25	D0 (LSB)	Digital Output Bit (L east Significant Bit)
26-33	D1-D8	Digital Output Bits
34, 35	GND	G round.
36, 37	DV_cc	+3.3 V/+5 V Power Supply (Digital). Powers output stage only.
38, 39	GND	G round.
40, 41	DV_CC	+3.3 V/+5 V Power Supply (Digital). Powers Output Stage only.
42, 43 44	D 9-D 10 D11 (M SB) ¹	Digital Output Bits. Digital Output Bit (Most Significant Bit).

NOTE

PIN CONFIGURATION



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¹Output coded as twos complement.